Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/526,314	HIBINO ET AL.	
Examiner	Art Unit	
Tan Ho	2821	

	SEAR	CHED	
Class	Subclass	Date	Examiner
343	850	3/406	T.H.
	860		
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	17.3 32	4	1

INT	INTERFERENCE SEARCHED					
Class	Subclass	ass Date		Examiner		
343	8.20	3/4	106	τ	.H.	
	860					
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3/4/06	T.H.
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